



Sheet 1 of 1

FORM PTO-1449  
(Rev. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

Atty. Docket No. 14641

Serial No.  
10/797,607**LIST OF PRIOR ART CITED BY APPLICANT**  
(Use several sheets if necessary)

APPLICANT Mandelis et al.

FILING DATE 3/11/2004

GROUP 2884

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
OG	AA	5667300	9/16/1997	Mandelis et al.			
OG	AB	5302830	4/12/1994	Shivanandan			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCL ASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		
	AT		

EXAMINER

*Paul G. L.*

DATE CONSIDERED

12/01/05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 602; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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APPLICANT Mandelis et al.

FILING DATE March 11, 2004

GROUP 2878

7884

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
	AD													
	AE													
	AF													

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

OG	AG	"Dynamics of the plasma and thermal waves in surface-modified semiconductors (invited)", Salnick et al., Rev. of Scientific Instruments, Vol. 74 (1), Jan. 2003, pgs. 545-549.
OG	AH	"Non-contacting measurements of photocarrier lifetimes in bulk- and polycrystalline thin-film Si photoconductive devices by photothermal radiometry", Mandelis et al., J. Appl. Phys. Vol. 80 (9), Nov 1. 1996, pgs. 5332-5341.
OG	AI	"Relative sensitivity of photomodulated reflectance and photothermal infrared radiometry to thermal and carrier plasma waves in semiconductors", Salnick et al., J. Appl. Phys. Vol. 82 (4), Aug 15, 1997, pgs. 1853-1859.
OG	AJ	"Theoretical and experimental aspects of three-dimensional infrared photothermal radiometry of semiconductors", J. Appl. Phys. Vol 85 (10), Ikari et al., May 15, 1999, pgs. 7392-7397.
OG	AK	"Minority carrier lifetime and iron concentration measurements on p-Si wafers by infrared photothermal radiometry and microwave photoconductance decay", Rodriguez et al., J. Appl Phys. Vol 87 (11), June 1, 2000, pgs. 8113-8121.
OG	AL	"Lock-in common-mode rejection demodulation: Measurement technique and applications to thermal-wave detection: Theoretical", Mandelis et al., Rev of Scientific Instruments Vol 71 (6), June 2000, pgs 2440-2444.

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